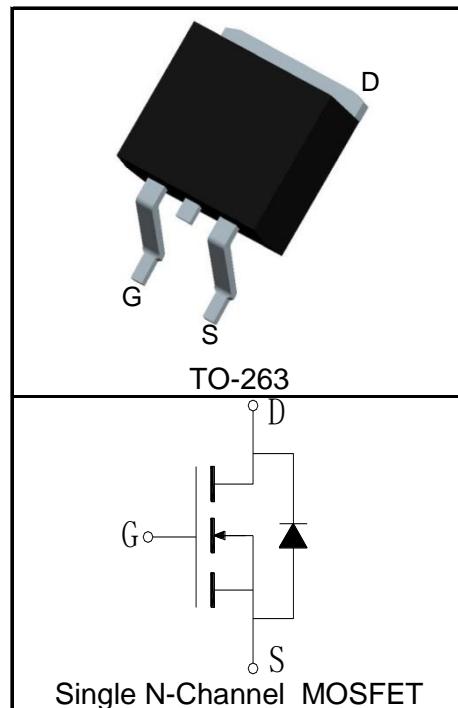


Features

- 80V/150A,
- $R_{DS(ON)} = 4m\Omega$ (Typ.)@ $V_{GS}=10V$
- Low $R_{DS(ON)}$
- Super High Dense Cell Design
- Reliable and Rugged
- 100% Avalanche Tested

Pin Description



Applications

- Power Switching Application
- Load Switching



Halogen-Free

Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit
Common Ratings ($T_c=25^\circ C$ Unless Otherwise Noted)			
V_{DSS}	Drain-Source Voltage	80	V
V_{GSS}	Gate-Source Voltage	± 20	
T_J	Maximum Junction Temperature	175	$^\circ C$
T_{STG}	Storage Temperature Range	-55 to 175	$^\circ C$
I_S	Diode Continuous Forward Current	$T_c=25^\circ C$	150
			A
Mounted on Large Heat Sink			
$I_{DP}^{①}$	300 μs Pulse Drain Current Tested	$T_c=25^\circ C$	600
$I_D^{②}$	Continuous Drain Current($V_{GS}=10V$)	$T_c=25^\circ C$	150
		$T_c=100^\circ C$	106
P_D	Maximum Power Dissipation	$T_c=25^\circ C$	214
		$T_c=100^\circ C$	107
$R_{\theta JC}$	Thermal Resistance-Junction to Case	0.7	$^\circ C/W$
$R_{\theta JA}^{③}$	Thermal Resistance-Junction to Ambient	62.5	$^\circ C/W$
Drain-Source Avalanche Ratings			
$E_{AS}^{④}$	Avalanche Energy, Single Pulsed	484	mJ

Electrical Characteristics ($T_C=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Condition	KS8202GE			Unit
			Min.	Typ.	Max.	
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_{\text{DS}}=250\mu\text{A}$	80			V
I_{DSS}	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=80\text{V}, \text{V}_{\text{GS}}=0\text{V}$			1	μA
		$\text{T}_J=125^\circ\text{C}$			30	
$\text{V}_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{DS}}=250\mu\text{A}$	2		4	V
I_{GSS}	Gate Leakage Current	$\text{V}_{\text{GS}}=\pm 20\text{V}, \text{V}_{\text{DS}}=0\text{V}$			± 100	nA
$\text{R}_{\text{DS}(\text{ON})}^{(5)}$	Drain-Source On-state Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{DS}}=40\text{A}$		4	5.5	$\text{m}\Omega$
Diode Characteristics						
$\text{V}_{\text{SD}}^{(5)}$	Diode Forward Voltage	$\text{I}_{\text{SD}}=40\text{A}, \text{V}_{\text{GS}}=0\text{V}$		0.83	1.2	V
t_{rr}	Reverse Recovery Time	$\text{I}_{\text{SD}}=40\text{A}, \frac{d\text{I}_{\text{SD}}}{dt}=100\text{A}/\mu\text{s}$		48		ns
Q_{rr}	Reverse Recovery Charge			85		nC
Dynamic Characteristics ⁽⁶⁾						
R_G	Gate Resistance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=0\text{V}, \text{F}=1\text{MHz}$		1		Ω
C_{iss}	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=40\text{V}, \text{Frequency}=1.0\text{MHz}$		3900		pF
C_{oss}	Output Capacitance			405		
C_{rss}	Reverse Transfer Capacitance			210		
$\text{t}_{\text{d}(\text{ON})}$	Turn-on Delay Time	$\text{V}_{\text{DD}}=40\text{V}, \text{I}_{\text{DS}}=20\text{A}, \text{V}_{\text{GEN}}=10\text{V}, \text{R}_G=6\Omega$		18		ns
t_r	Turn-on Rise Time			28		
$\text{t}_{\text{d}(\text{OFF})}$	Turn-off Delay Time			45		
t_f	Turn-off Fall Time			26		
Gate Charge Characteristics ⁽⁶⁾						
Q_g	Total Gate Charge	$\text{V}_{\text{DS}}=40\text{V}, \text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{DS}}=40\text{A}$		64		nC
Q_{gs}	Gate-Source Charge			12		
Q_{gd}	Gate-Drain Charge			21		

Notes:

- ①Pulse width limited by safe operating area.

- ②Calculated continuous current based on maximum allowable junction temperature. The package limitation current is 75A.

- ③When mounted on 1 inch square copper board, $t \leq 10\text{sec}$. The value in any given application depends on the user's specific board design.

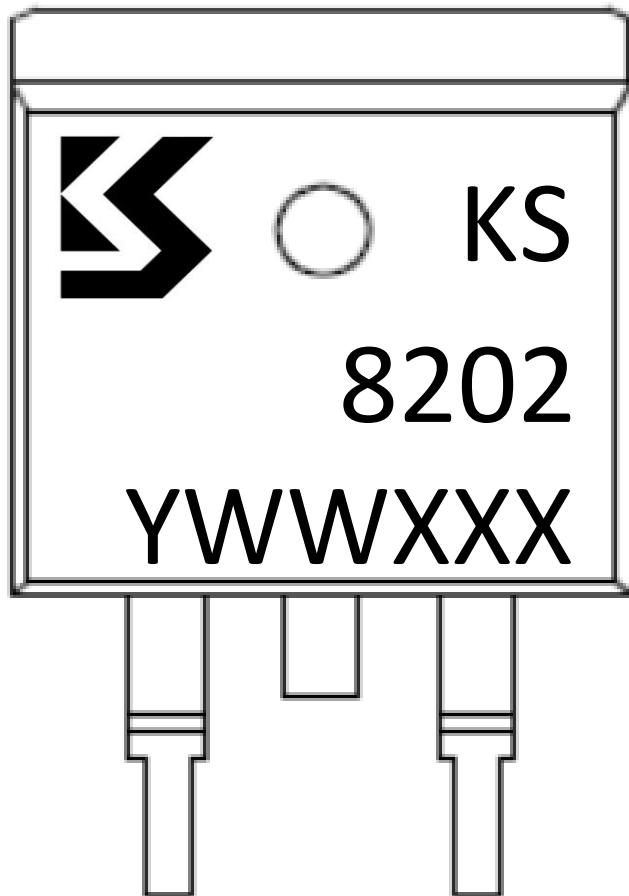
- ④Limited by $T_{J\text{max}}, I_{AS} = 44\text{A}, L=0.5\text{mH}, V_{DD} = 48\text{V}, R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$.

- ⑤Pulse test; Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.

- ⑥Guaranteed by design, not subject to production testing.

Ordering and Marking Information

Device	Package	Packaging	Quantity	Reel Size	Tape width
KS8202GE	TO-263	Tape&Reel	800	13"	24mm

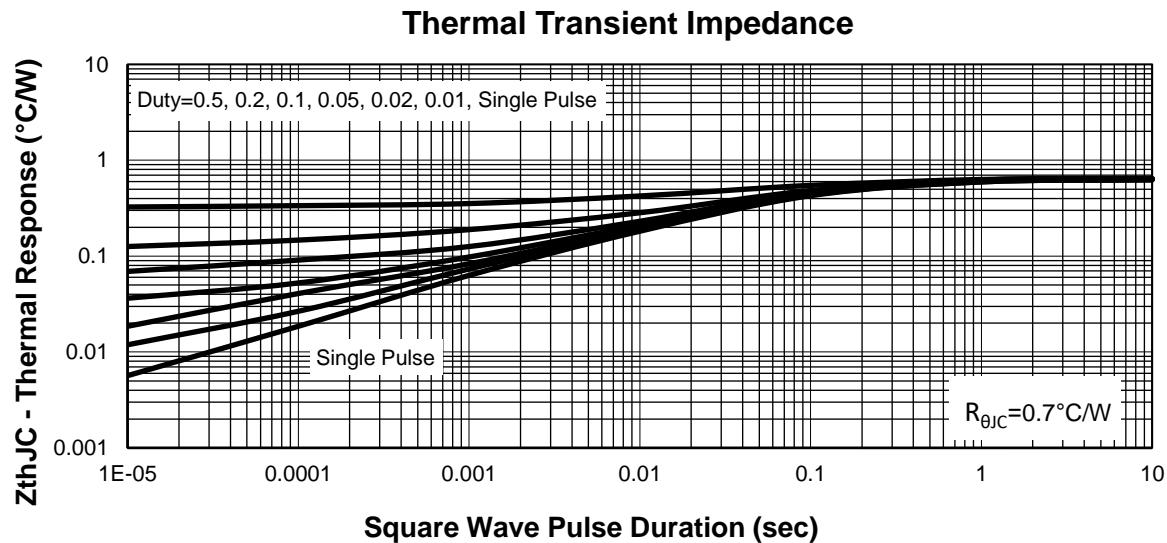
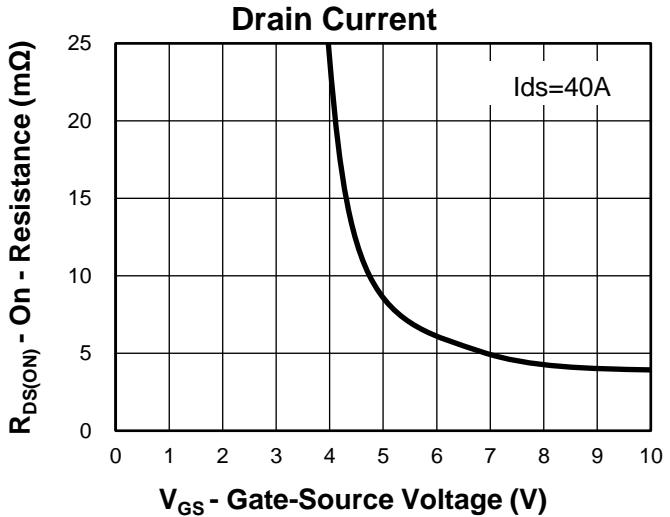
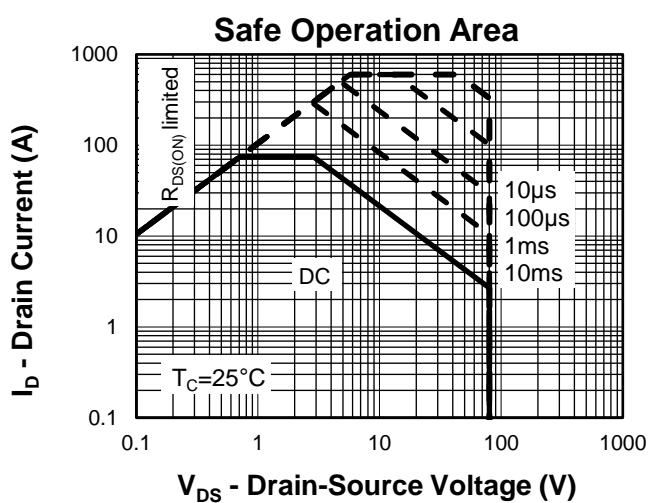
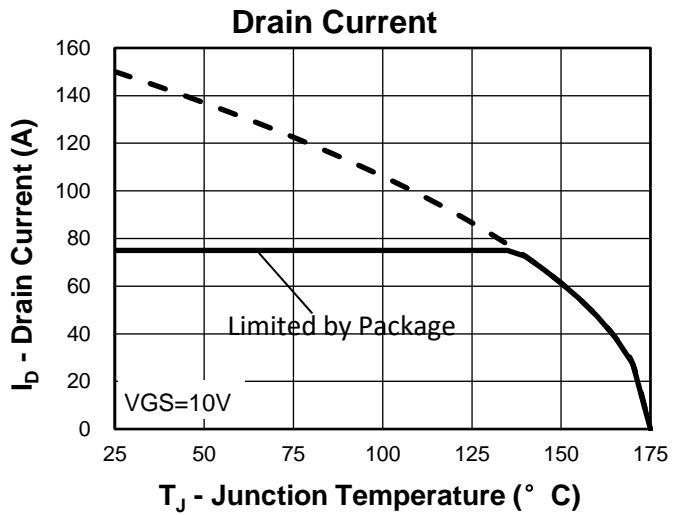
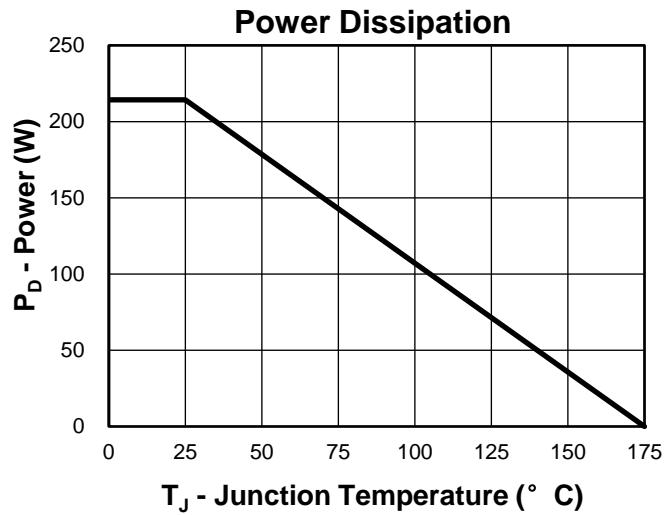


Y =Year,2017-A,2018-B,etc.

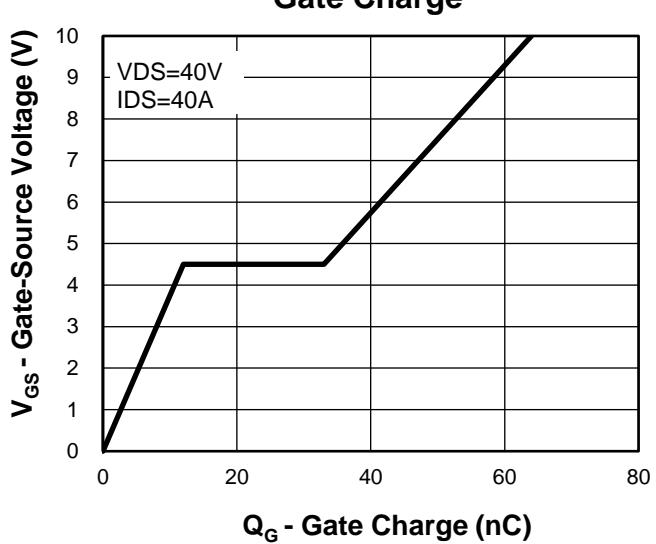
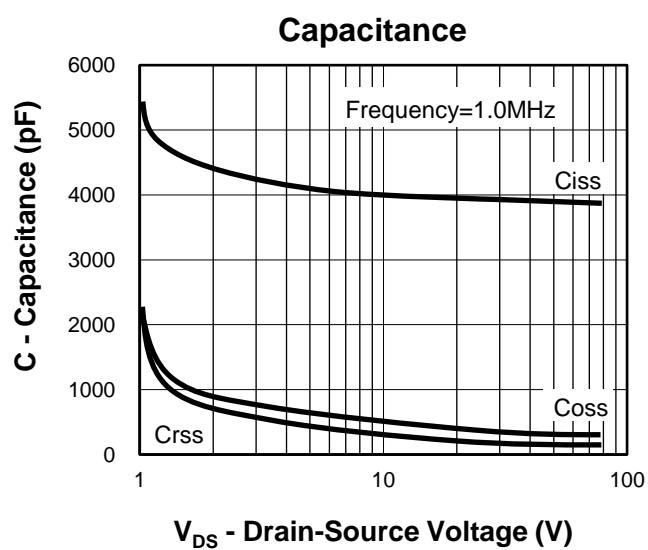
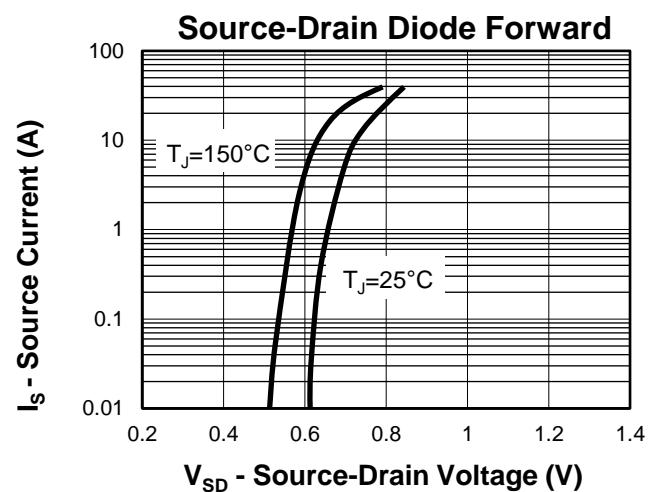
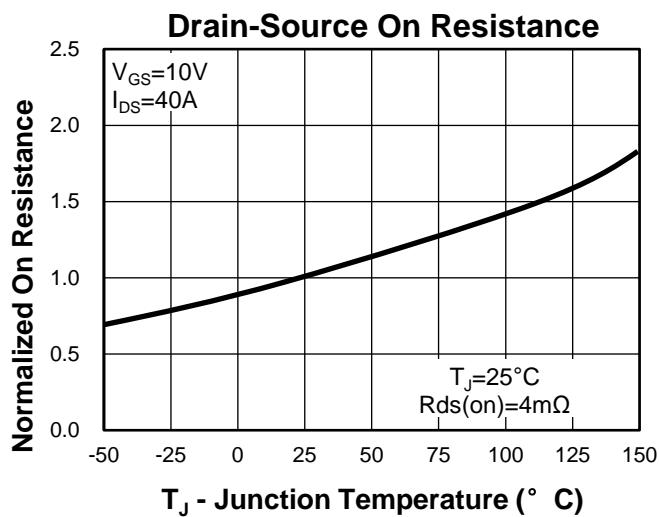
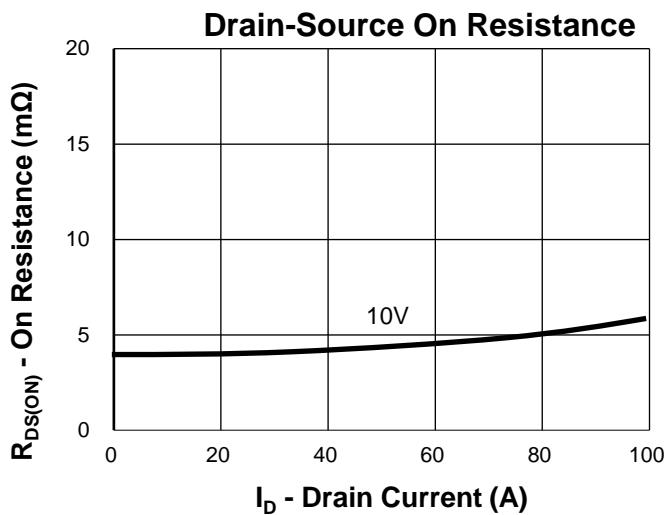
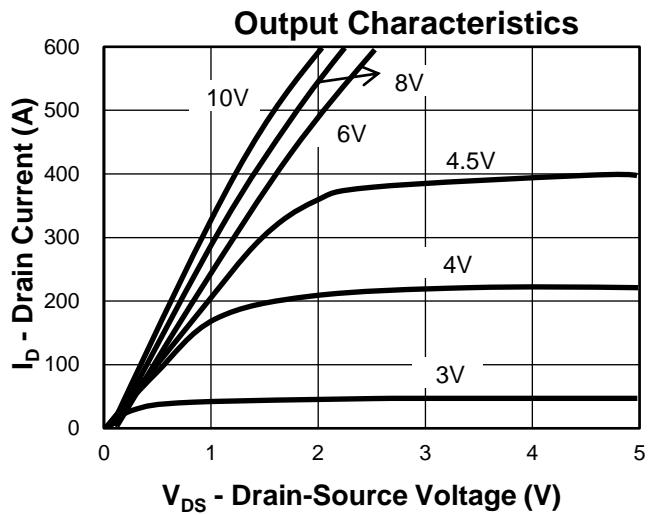
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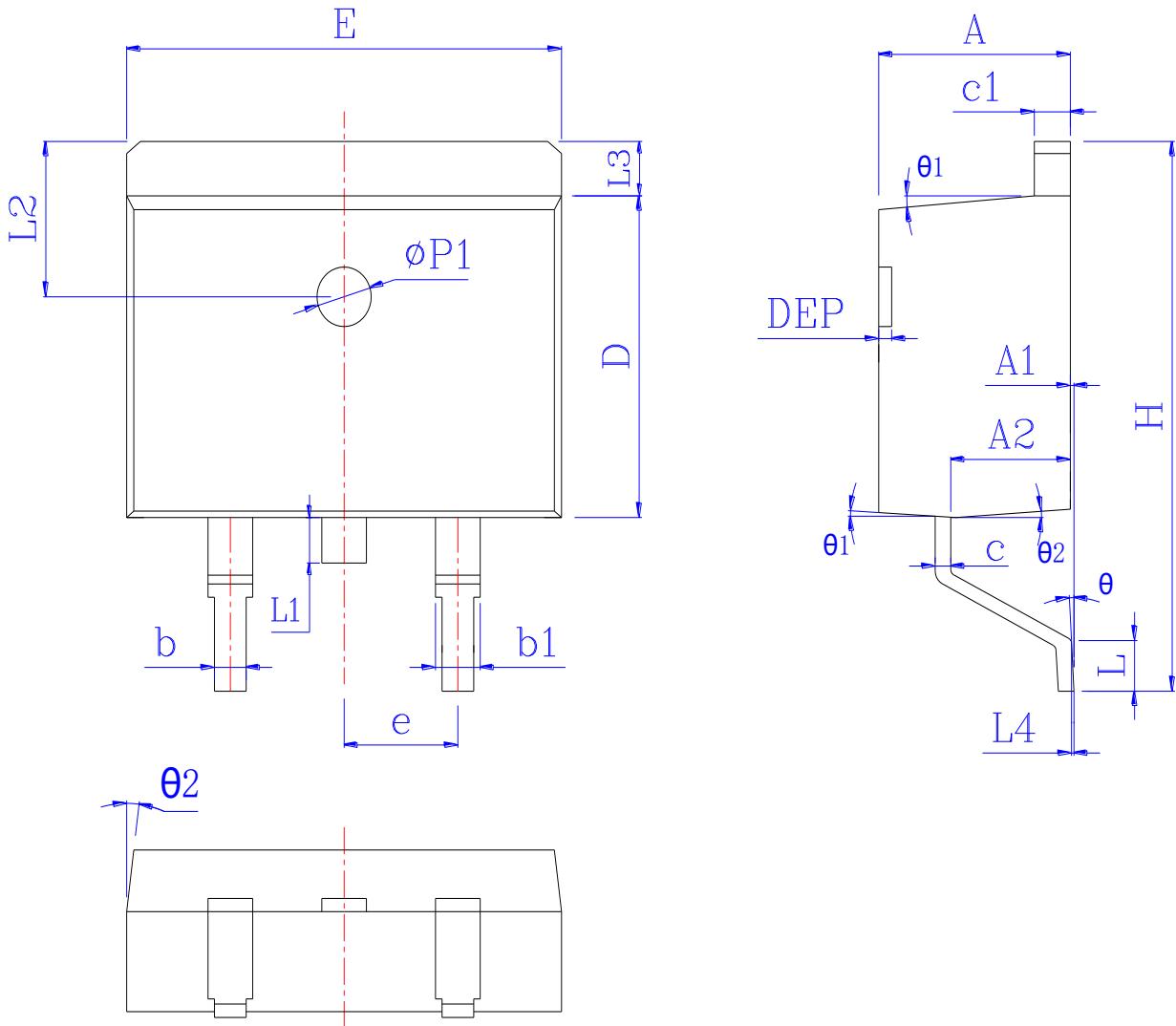
XXX =Lot number.

Typical Characteristics



Typical Characteristics



Package Information
TO-263


SYMBOL	MM			INCH			SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX		MIN	NOM	MAX	MIN	NOM	MAX
A	4.40	4.55	4.72	0.173	0.179	0.186	L	1.94	2.30	2.60	0.076	0.091	0.102
A1	0.00	0.10	0.25	0.000	0.005	0.010	L3	1.17	1.29	1.40	0.046	0.051	0.055
A2	2.59	2.69	2.79	0.102	0.106	0.110	L1	*	*	1.70	*	*	0.067
b	0.76	*	0.90	0.030	*	0.035	L4	0.25 BSC			0.01 BSC		
b1	1.22	*	1.36	0.048	*	0.054	L2	2.50 REF			0.098 REF		
c	0.33	*	0.47	0.013	*	0.019	θ	0°	*	8°	0°	*	8°
c1	1.22	*	1.32	0.048	*	0.052	θ1	5°	7°	9°	5°	7°	9°
D	8.60	*	9.29	0.339	*	0.366	θ2	1°	3°	5°	1°	3°	5°
E	9.95	*	10.26	0.392	*	0.404	DEP	0.05	0.10	0.20	0.002	0.004	0.008
e	2.54BSC			0.100BSC			Φp1	1.40	1.50	1.60	0.055	0.059	0.063
H	14.70	15.10	15.79	0.579	0.594	0.622							

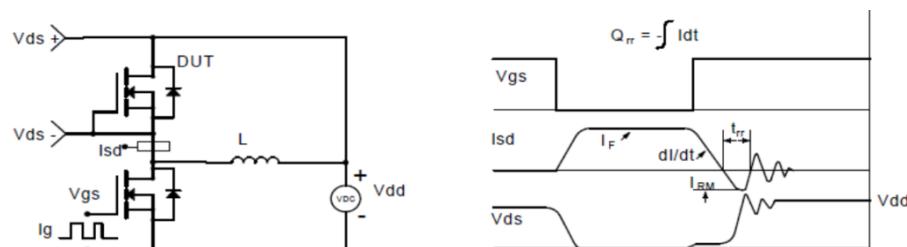
Avalanche Test Circuit and Waveforms



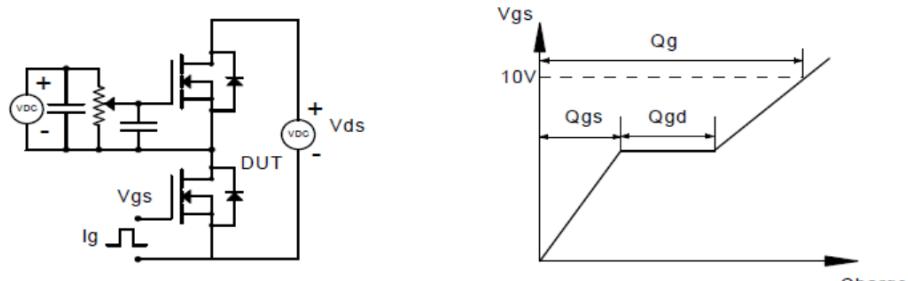
Switching Time Test Circuit and Waveforms



Diode Recovery Test Circuit and Waveforms



Gate Charge Test Circuit and Waveform



Customer Service

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